

Fake Background estimation in $W^{\pm}Z$ diboson production

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ΑΡΙΣΤΟΤΕΛΕΙΟ
ΠΑΝΕΠΙΣΤΗΜΙΟ
ΘΕΣΣΑΛΟΝΙΚΗΣ



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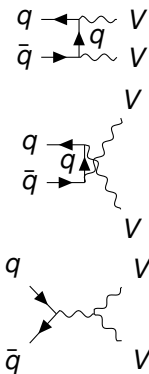


June 18, 2021

Motivation

- ▽ Motivation for Diboson Processes:
 - EWSB probe at TeV scale
 - Sensitive to aTGCs / aQGCs
 - Polarization

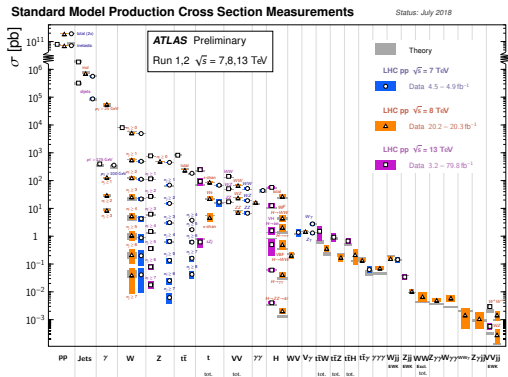
Diboson Production (LO)



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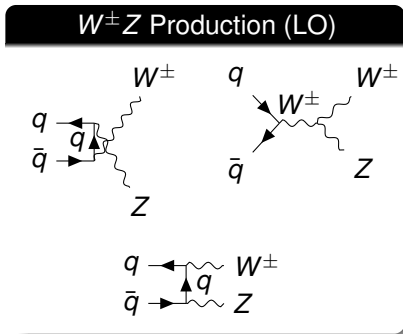
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▽ and especially $W^\pm Z$:

- $\frac{\sigma_{W^\pm Z}}{\sigma_{W^- Z}}$
- NLO & NNLO corrections
(1604.08576)



| \sqrt{s} | σ_{LO} [pb] | σ_{NLO} [pb] | σ_{NNLO} [pb] | σ_{NLO}/σ_{LO} | $\sigma_{NNLO}/\sigma_{NLO}$ |
|------------|---|---|--|----------------------------|------------------------------|
| 7 | 11.354(1) ^{+0.5%} _{-1.2%} | 18.500(1) ^{+5.3%} _{-4.1%} | 19.973(13) ^{+1.7%} _{-1.9%} | +62.9% | + 8.0% |
| 8 | 13.654(1) ^{+1.3%} _{-2.1%} | 22.750(2) ^{+5.1%} _{-3.9%} | 24.690(16) ^{+1.8%} _{-1.9%} | +66.6% | + 8.5% |
| 13 | 25.517(2) ^{+4.3%} _{-5.3%} | 46.068(3) ^{+4.9%} _{-3.9%} | 51.11(3) ^{+2.2%} _{-2.0%} | +80.5% | +10.9% |
| 14 | 27.933(2) ^{+4.7%} _{-5.7%} | 51.038(3) ^{+5.0%} _{-4.0%} | 56.85(3) ^{+2.3%} _{-2.0%} | +82.7% | +11.4% |

Table 1: Total on-shell $W^\pm Z$ cross sections at LO, NLO and NNLO for relevant collider energies. The last two columns contain the relative corrections at NLO and NNLO, respectively.

Event Selection

W[±]Z Inclusive Event Selection

Event Selection

| <i>W[±]Z</i> Inclusive Event Selection | |
|--|---|
| Event Cleaning | Reject LAr, Tile and SCT corrupted / incomplete events |
| Trigger and Vertex | Hard scattering vertex with $N_{\text{Tracks}} \geq 2$ Event must fire e/μ HLT |

Event Selection

■ $ll\nu$ signature

3 sets of lepton selection cuts:

- **Baseline:** $p_T > 5$ GeV, basic quality & isolation, overlap removal with other leptons etc.
- **Z-type:** $p_T > 15$ GeV, better quality & isolation, OLR with selected jets etc.
- **W-type:** $p_T > 20$ GeV, tighter quality criteria and stricter isolation

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| ZZ veto | < 4 Baseline-Selection Leptons |
| $ll\nu$ signature | Exactly 3 leptons passing Z lepton selection |
| Leading p_T | $p_T^{lead} > 27$ GeV (25 GeV for data / MC from 2015) |

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| Z-decay leptons | Pair of SFOC leptons passing Z selection |
| Z Mass Window | $ M_{ll} - M_Z < 10$ GeV |

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| Z-decay leptons | Pair of SF0C leptons passing Z selection |
| Z Mass Window | $ M_l - M_Z < 10$ GeV |
| W^\pm lepton | Remaining lepton passes W^\pm selection |
| W^\pm Transverse Mass | $m_T^W > 30$ GeV |

Backgrounds

- Distinguish depending on final state (FS) leptons:

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Reducible - ≥ 1 fake FS lepton

- 1 Heavy / Light flavour jets mis-identified as leptons
- 2 Leptons (electrons) from photon conversion

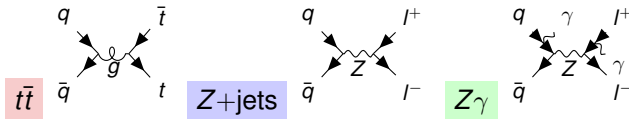
Backgrounds

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Matrix Method for Background Estimation

- The Matrix Method (MM) is a way to estimate the contribution of background processes to the SR without relying on Monte Carlo simulation.
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 - MM is a **data-driven method** to estimate such backgrounds

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Toy single Bkg. Case

- Assuming SR selection C , expect: $\nu(C)$ events in total
- Create selection D targeting B :

$$\nu_{\text{sel}}(C) = \epsilon_C \nu_S + \epsilon_{C,B} \nu_B$$

$$\nu_{\text{sel}}(D) = \epsilon_D \nu_S + \epsilon_{D,B} \nu_B$$

- Substitute the selection efficiency

$$\nu(C) = \epsilon_C \nu_S + \epsilon_{C,B} \nu_B$$

- Solve for ν_B by inverting the efficiency matrix

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- Solve for ν_B by inverting the efficiency matrix
 - $$\nu = \epsilon^{-1} \nu_{\text{sel}}$$

- In $W^\pm Z$ production, any of the leptons assigned to the W or the Z can be a fake.

Notation: N_{RFR} denotes the number of events with a real lepton assigned to the W and the trailing Z -lepton, while the leading Z -lepton is fake

Matrix Method in $W^\pm Z$ production

1. Loose SR: Loosen the selection → enhance fakes

| Electrons | Muons |
|---|--|
| $p_T > 15 \text{ GeV}$ | $p_T > 15 \text{ GeV}$ |
| $ \eta < 2.47$ | $\eta < 2.7$ |
| $!(1.37 < \eta < 1.52)$ | - |
| pass Loose LH ID | Medium LH ID |
| $d_0^{\text{BL}}/\sigma(d_0^{\text{BL}}) < 5$ | $d_0^{\text{BL}}/\sigma(d_0^{\text{BL}}) < 3$ (if $\eta < 2.5$) |
| $z_0 < 0.5$ | $z_0 < 0.5$ (if $\eta < 2.5$) |

+ Isolation and/or Identification = Loose

- Loose lepton set disjoint from tight (SR) selection set

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2. Express selection combinations

$$\begin{pmatrix} N_{TTT} \\ N_{TTL} \\ N_{TTL} \\ N_{TLL} \\ N_{TLL} \\ N_{LLT} \end{pmatrix} = \begin{pmatrix} e_1 e_2 e_3 & e_1 e_2 f_3 & e_1 f_2 e_3 & f_1 e_2 e_3 & e_1 f_2 f_3 & f_1 e_2 f_3 & f_1 f_2 e_3 & f_1 f_2 e_3 \\ e_1 e_2 \bar{e}_3 & e_1 e_2 \bar{f}_3 & e_1 f_2 \bar{e}_3 & f_1 e_2 \bar{e}_3 & e_1 f_2 \bar{f}_3 & f_1 e_2 \bar{f}_3 & f_1 f_2 \bar{e}_3 & f_1 f_2 \bar{e}_3 \\ e_1 \bar{e}_2 e_3 & e_1 \bar{e}_2 f_3 & e_1 f_2 e_3 & f_1 \bar{e}_2 e_3 & e_1 \bar{f}_2 f_3 & f_1 \bar{e}_2 f_3 & f_1 \bar{f}_2 e_3 & f_1 \bar{f}_2 e_3 \\ \bar{e}_1 e_2 e_3 & \bar{e}_1 e_2 f_3 & \bar{e}_1 f_2 e_3 & f_1 e_2 e_3 & \bar{e}_1 f_2 f_3 & f_1 e_2 f_3 & \bar{f}_1 e_2 e_3 & \bar{f}_1 e_2 e_3 \\ e_1 \bar{e}_2 \bar{e}_3 & e_1 \bar{e}_2 \bar{f}_3 & e_1 f_2 \bar{e}_3 & f_1 \bar{e}_2 \bar{e}_3 & e_1 f_2 \bar{f}_3 & f_1 \bar{e}_2 \bar{f}_3 & \bar{f}_1 e_2 \bar{e}_3 & \bar{f}_1 e_2 \bar{e}_3 \\ \bar{e}_1 \bar{e}_2 e_3 & \bar{e}_1 \bar{e}_2 f_3 & \bar{e}_1 f_2 e_3 & f_1 \bar{e}_2 e_3 & \bar{e}_1 f_2 f_3 & f_1 \bar{e}_2 f_3 & \bar{f}_1 e_2 e_3 & \bar{f}_1 e_2 e_3 \\ \bar{e}_1 \bar{e}_2 \bar{e}_3 & \bar{e}_1 \bar{e}_2 \bar{f}_3 & \bar{e}_1 f_2 \bar{e}_3 & f_1 \bar{e}_2 \bar{e}_3 & \bar{e}_1 f_2 \bar{f}_3 & f_1 \bar{e}_2 \bar{f}_3 & \bar{f}_1 e_2 \bar{e}_3 & \bar{f}_1 e_2 \bar{e}_3 \end{pmatrix} \begin{pmatrix} N_{RRR} \\ N_{RRF} \\ N_{RRF} \\ N_{RRF} \\ N_{RRF} \\ N_{RRF} \\ N_{RRF} \\ N_{RRF} \end{pmatrix}$$

- Select real as tight → e
- Select fake as tight → f
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- Select real as tight $\rightarrow e$
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3. Matrix Method N_{fake} estimate equation

$$N_{\text{fake}} = N_{TTL}^{\text{red}} F_Z + N_{TLL}^{\text{red}} F_Z + N_{LTT}^{\text{red}} F_W - N_{TLL}^{\text{red}} F_Z F_Z - N_{LTL}^{\text{red}} F_W F_Z - N_{LTL}^{\text{red}} F_W F_Z - N_{LLT}^{\text{red}} F_W F_Z$$

\uparrow Define Fake Factors $F_{Z/W} = \frac{f}{\bar{f}} = \frac{N_T}{N_{\bar{T}}}$

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Strategy

- 3 sources of reducible background \rightarrow 3 FFs
- CR rich in non-prompt leptons \rightarrow Fake Factor
- A value combining 3 FFs is substituted in (3) to estimate N_{fake}

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\uparrow Define Fake Factors $F_{Z/W} = \frac{f}{\bar{f}} = \frac{N_T}{N_{\bar{T}}}$

Control Regions

- **Z+jets**: Create Z-pair by selecting 2 likely prompt leptons and a non-isolated lepton

- **$t\bar{t}$** : Select two likely prompt leptons from $t \rightarrow Wb$, while avoiding SFOC pairs.

- **$Z\gamma$** : Similar to Z+jets CR, however use m_{ll} window below M_Z and an m_{3l} cut.

≥ 2 Z-type leptons, same-flavour and opposite charge (e^+e^- or $\mu^+\mu^-$)

$$|m_{ll} - m_Z^{PDG}| < 15 \text{ GeV}$$

fake lepton is highest- p_T Matrix Method lepton

fake electron

$$m_T^W < 30 \text{ GeV}$$

$$E_T^{\text{miss}} < 30 \text{ GeV}$$

$$m_{ll} > 81 \text{ GeV}$$

fake muon

$$m_T^W < 30 \text{ GeV}$$

-

-

≥ 1 Z-type electron e_Z

≥ 1 Z-type muon μ_Z

$$\text{charge}(\mu_Z) \cdot \text{charge}(e_Z) < 0$$

remaining highest- p_T Matrix Method lepton \equiv fake lepton ℓ_m

lepton with different flavour than fake lepton passes W-lepton requirements: ℓ_W

$$\text{charge}(\ell_m) \cdot \text{charge}(\ell_W) > 0$$

≥ 2 Z-type muons, opposite charge ($\mu^+\mu^-$)

$$55 < m_{ll} < 85 \text{ GeV}$$

$$m_{3l} < 105 \text{ GeV}$$

fake lepton is highest- p_T Matrix Method electron

$$m_T^W < 30 \text{ GeV}$$

$$E_T^{\text{miss}} < 30 \text{ GeV}$$

Fake Factors for $t\bar{t}$ / Z +jets / $Z\gamma$

$$\text{FF}_{\text{Data}} = \frac{N_{T, \text{Data}} - N_{T, \text{RL\&ND } t\bar{t}/Z+\text{jets}/Z\gamma} - N_{T, \text{Irr. MC}}}{N_{!T, \text{Data}} - N_{!T, \text{RL\&ND } t\bar{t}/Z+\text{jets}/Z\gamma} - N_{!T, \text{Irr. MC}}}$$

$$\text{FF}_{\text{MC}} = \frac{N_{T, t\bar{t}/Z+\text{jets}/Z\gamma} - N_{T, \text{RL\&ND } t\bar{t}/Z+\text{jets}/Z\gamma}}{N_{!T, t\bar{t}/Z+\text{jets}/Z\gamma} - N_{!T, \text{RL\&ND } t\bar{t}/Z+\text{jets}/Z\gamma}}$$

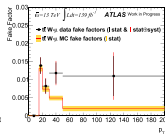
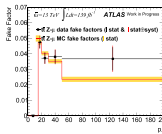
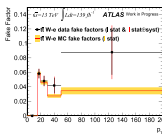
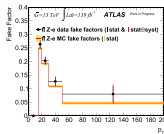
Fake Factors for $t\bar{t}$ / Z +jets / $Z\gamma$

$$\text{FF}_{\text{Data}} = \frac{N_{T, \text{Data}} - N_{T, \text{RL\&ND } t\bar{t}/Z+\text{jets}/Z\gamma} - N_{T, \text{Irr. MC}}}{N_{!T, \text{Data}} - N_{!T, \text{RL\&ND } t\bar{t}/Z+\text{jets}/Z\gamma} - N_{!T, \text{Irr. MC}}$$

● data fake factors (| stat & | stat ⊕ syst)

■ MC fake factors (| stat)

$t\bar{t}$





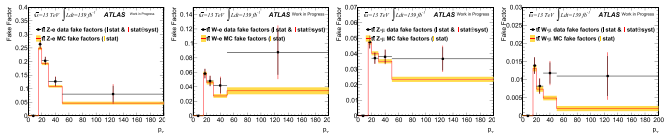
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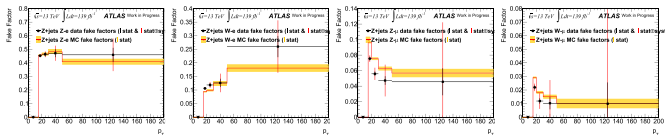
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Z +jets





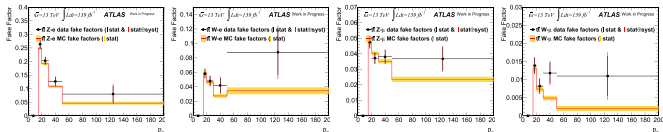
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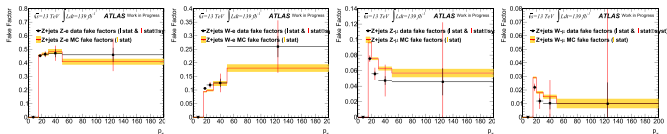
● data fake factors (| stat & | stat ⊕ syst)

■ MC fake factors (| stat)

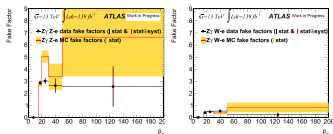
$t\bar{t}$



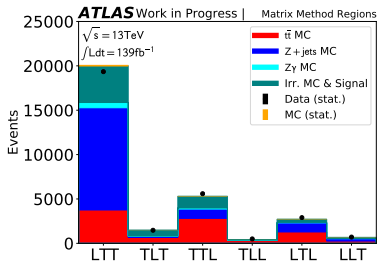
Z +jets



$Z\gamma$



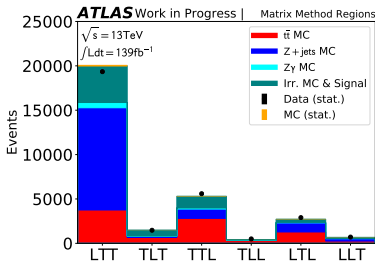
Expected Composition of Loose SR



← Z+jets fake background contribution is dominant, followed by $t\bar{t}$

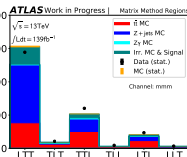
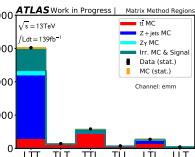
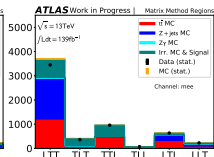
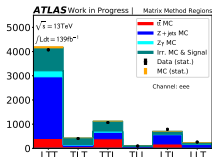


Expected Composition of Loose SR



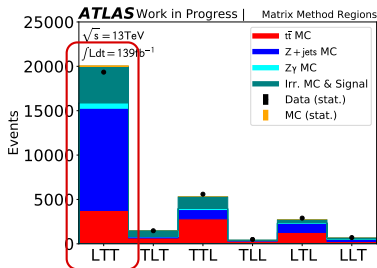
← Z+jets fake background contribution is dominant, followed by $t\bar{t}$

↓ Composition of Loose SR, per leptonic channel



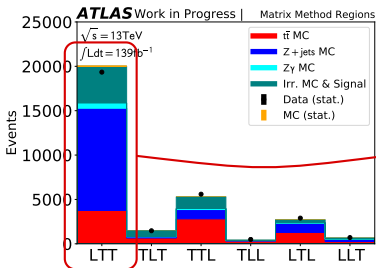
Composition-Weighted Average

- Utilize MC-based composition information



Composition-Weighted Average

- Utilize MC-based composition information
- in combining 3 Fake Factors



Average Fake Factors with Exp. Composition

Combined $FF =$

$$\begin{aligned}
 & FF_{Z+\text{jets}} \times (\% Z + \text{jets}) \\
 & + FF_{Z\gamma} \times (\% Z\gamma) \\
 & + FF_{t\bar{t}} \times (\% t\bar{t})
 \end{aligned}$$

Composition-Weighted Average

- Utilize MC-based composition information
- in combining 3 Fake Factors

In the end:

- 1 combined FF per Loose SR region
 - FF_{LTT}, FF_{TLT} etc.

Average Fake Factors with Exp. Composition

$$\begin{aligned} \text{Combined } FF = & \\ & FF_{Z+\text{jets}} \times (\% Z + \text{jets}) \\ & + FF_{Z\gamma} \times (\% Z\gamma) \\ & + FF_{t\bar{t}} \times (\% t\bar{t}) \end{aligned}$$

$|\eta|$ -Dependence

- Ideally: Fake Factors calculated in 2-D bins of $p_T - \eta$

$|\eta|$ -Dependence

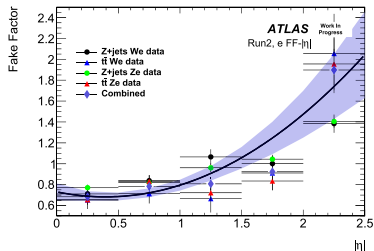
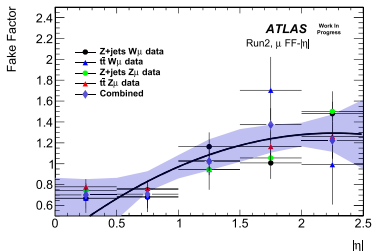
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$|\eta|$ -Dependence

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Symmetric dependence: $FF \rightarrow F(|\eta|) \times FF$

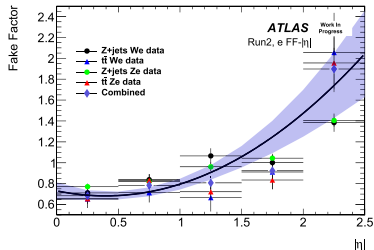
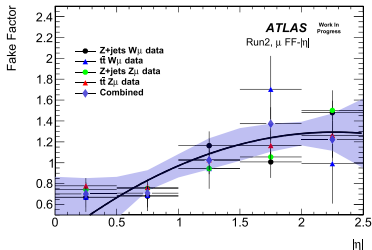
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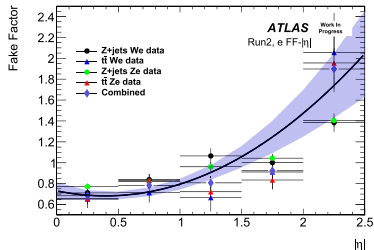
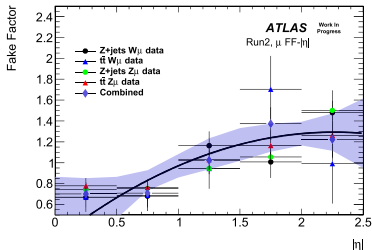
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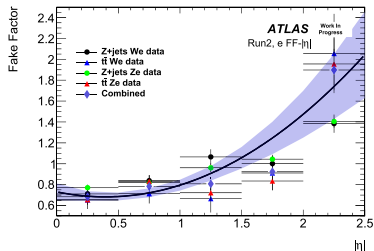
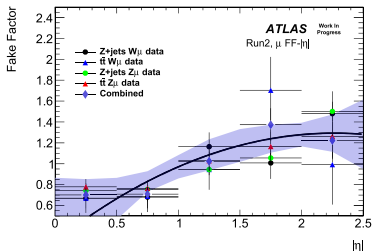
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 1σ error band used to evaluate the systematic uncertainty of this correction

Systematics

Breakdown

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--------|----------------------------|----------|-----------|-------------|-----|
| | Relative uncertainties [%] | | | | |

Systematics

1 Statistical Uncertainties of the FFs 0.5% to 4%

Breakdown

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|----------------------------|-------|----------|-----------|-------------|------|
| Relative uncertainties [%] | | | | | |
| F_W muon | 0.00 | 2.95 | 0.00 | 4.36 | 0.55 |
| F_Z muon | 0.00 | 0.00 | 0.32 | 2.31 | 0.31 |
| F_W electron | 3.18 | 0.00 | 5.29 | 0.00 | 3.56 |
| F_Z electron | 2.75 | 3.46 | 0.00 | 0.00 | 1.27 |

Systematics

- 1 Statistical Uncertainties of the FFs
0.5% to 4%
- 2 15% cross-section uncertainty in Irreducible Subtraction in CR and SR
17% (35% in $\mu\mu\mu$)

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9% for electron fakes
1% for muon fakes

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| Correlated η correction (e) | 9.70 | 8.14 | 9.89 | 0.00 | 8.87 |
| Correlated η correction (μ) | 0.00 | 1.90 | 0.58 | 10.24 | 1.21 |

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17% (35% in $\mu\mu\mu$)

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9% for electron fakes

1% for muon fakes

4 Uncertainty assigned to Weighted Average

→ Expected Composition: 6.5%

Vary expected reducible background yields by their statistical uncertainty

Breakdown

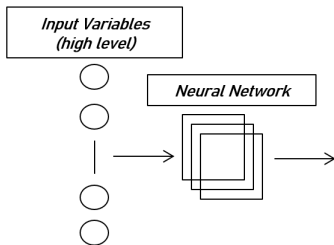
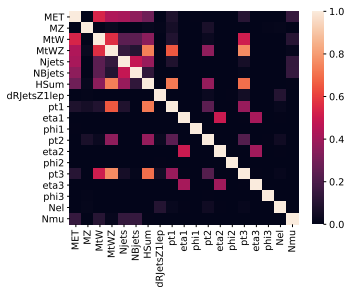
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| Correlated η correction (μ) | 0.00 | 1.90 | 0.58 | 10.24 | 1.21 |
| W. Average Stat. Uncertainty | 6.27 | 12.89 | 5.29 | 13.97 | 6.48 |
| Total sys. | 18.85 | 30.82 | 21.38 | 39.90 | 20.99 |
| Stat. | 2.88 | 5.48 | 1.78 | 1.66 | 1.52 |
| Total | 19.07 | 31.30 | 21.45 | 39.94 | 21.05 |
| Absolute uncertainties | | | | | |
| Total | 150.49 | 35.68 | 155.19 | 58.68 | 373.30 |

Multivariate per-event Weighted Average

- Idea: Utilize data-driven composition of Fake Background in W.A.

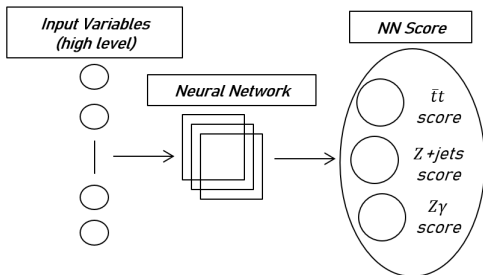
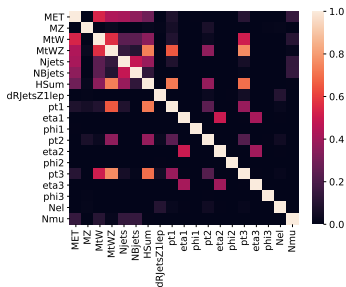
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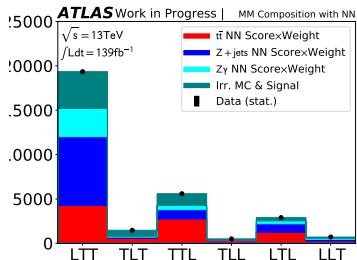
Average Fake Factors with NN Score

Combined $FF =$

$$\begin{aligned} & FF_{Z+\text{jets}} \times (Z + \text{jets NN score}) \\ & + FF_{Z\gamma} \times (Z\gamma \text{ NN score}) \\ & + FF_{t\bar{t}} \times (t\bar{t} \text{ NN score}) \end{aligned}$$

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- The per-event NN score triplet can be used to provide a data-driven Reducible Background composition.

Performance of trained Classifiers

Train-Test N_{events} (80 – 20)

| | $Z+\text{jets}$ | $Z\gamma$ | $t\bar{t}$ |
|-------|-----------------|-----------|------------|
| Train | 41766 | 2988 | 47756 |
| Test | 10442 | 747 | 11939 |
| Val. | 13052 | 934 | 14924 |

NN Architecture

| Num. Layers | Nodes | Drop-out | Batch Size |
|-------------|-------|----------|------------|
| 2 | 256 | 40% | 1024 |

Performance of trained Classifiers

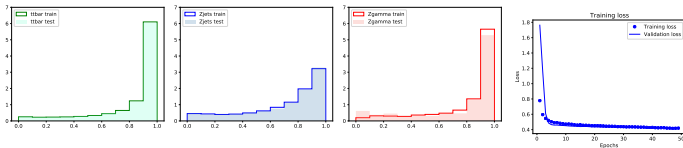
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Train-Test set performance

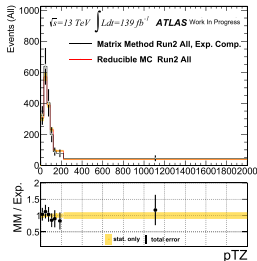
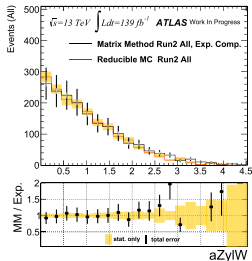


- Train-test distributions indicate smooth learning
- $Z+\text{jets}$ train-test curves flatter than $t\bar{t} / Z\gamma$

$Z+\text{jets}$ mis-classification as $Z\gamma$ leads to larger estimates, due to large $Z\gamma$ FF values contributing through the $Z\gamma$ score

Results - Using Expected Composition

Exp. Composition FF Weighted Average



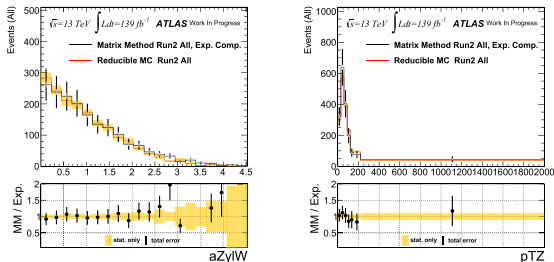
← Comparison of distribution of $|y_Z - y_W|$ and p_{TZ} with Expected Reducible MC, scaled with MC Scale Factors

Shown are MM stat. errors, MM total errors and MC stat. errors



Results - Using Expected Composition

Exp. Composition FF Weighted Average



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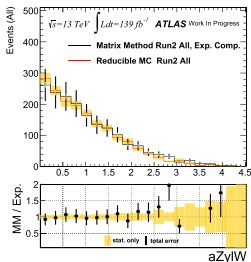
Shown are MM stat. errors, MM total errors and MC stat. errors

↓ Break-down of the result, localizing to each lepton channel.

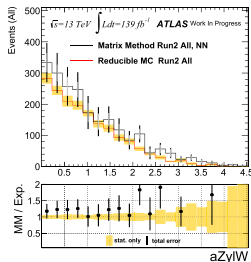
| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--|-------------------------------|-----------------------------|-------------------------------|-----------------------------|--------------------------------|
| $N_{LT} \cdot F_W$ | $478.3 \pm 11.0 \pm 108.9$ | $23.8 \pm 0.6 \pm 26.7$ | $683.5 \pm 12.8 \pm 153.2$ | $44.3 \pm 0.8 \pm 43.8$ | $1230.0 \pm 16.9 \pm 321.1$ |
| $N_{LT} \cdot F_Z$ | $87.7 \pm 13.1 \pm 36.1$ | $5.2 \pm 2.2 \pm 5.5$ | $7.8 \pm 0.6 \pm 1.7$ | $12.4 \pm 0.7 \pm 11.1$ | $113.1 \pm 13.3 \pm 43.5$ |
| $N_{TL} \cdot F_Z$ | $282.5 \pm 14.7 \pm 56.0$ | $87.6 \pm 5.8 \pm 15.9$ | $34.3 \pm 1.3 \pm 4.5$ | $90.8 \pm 2.2 \pm 14.1$ | $495.3 \pm 16.0 \pm 75.2$ |
| -2L Terms | $-59.3 \pm 2.8 \pm 20.1$ | $-2.7 \pm 0.2 \pm 1.7$ | $-2.2 \pm 0.1 \pm 0.8$ | $-0.6 \pm 0.0 \pm 0.4$ | $-64.8 \pm 2.8 \pm 22.5$ |
| Matrix Method result | $789.24 \pm 22.72 \pm 148.77$ | $113.99 \pm 6.25 \pm 35.13$ | $723.53 \pm 12.87 \pm 154.66$ | $146.92 \pm 2.44 \pm 58.62$ | $1773.68 \pm 26.96 \pm 372.33$ |
| $(\bar{t}\bar{t} + Z\text{jets} + Z\gamma)$ MC \times SF | 565.80 ± 25.70 | 198.00 ± 6.60 | 695.50 ± 31.60 | 270.60 ± 9.20 | 1730.00 ± 42.30 |

Comparison of results - Expected Comp. FF vs NN Score FF

Exp. Composition FF Weighted Average



NN Score FF Weighted Average



- NNscore combined FF is in general larger \leftrightarrow contribution from large $Z\gamma$ FF values
- Larger total errors with NN, despite no systematic from Expected Composition

Uncertainty due to limited Loose SR statistics $\leftarrow \sqrt{\sum_i (w_i \times FF_i)^2}$

- All-channel estimate still within error, per-channel discrepancies remain

Summary

- ▽ Two methods for estimating the background of the $W^\pm Z \rightarrow \bar{l}l'\nu_l$ analysis using the Matrix Method
 - Fake Factors are defined for 3 CRs and their combination is substituted in the Matrix Method equation for Loose SR events
 - The Fake Factors are combined with a weighted average using: either the Expected Composition of the Reducible Background or a Multivariate Classifier's scores

- ▽ Future Investigation
 - Investigation of Loose SR & CR selection leading to small fake- μ rates for $Z+\text{jets}$ and large Data and MC fake- e rates for $Z\gamma$
 - Damping of the $Z\gamma$ FF contribution in the NN score Matrix Method

$W^\pm Z$ Inclusive Object Selection

| Electron object selection | | | |
|---|--------------------|-------------|-------------|
| Selection | Baseline selection | Z selection | W selection |
| $p_T > 5 \text{ GeV}$ | ✓ | ✓ | ✓ |
| Electron object quality | ✓ | ✓ | ✓ |
| $ \eta^{\text{cluster}} < 2.47, \eta < 2.5$ | ✓ | ✓ | ✓ |
| Loose Layer identification | ✓ | ✓ | ✓ |
| $ d_0^{\text{BL}}/\sigma(d_0^{\text{BL}}) < 5$ | ✓ | ✓ | ✓ |
| $ \Delta z_0^{\text{BL}} \sin \theta < 0.5 \text{ mm}$ | ✓ | ✓ | ✓ |
| FCLoose isolation | ✓ | ✓ | ✓ |
| e-to- μ and e-to-e overlap removal | ✓ | ✓ | ✓ |
| e-to-jets overlap removal | | ✓ | ✓ |
| $p_T > 15 \text{ GeV}$ | | ✓ | ✓ |
| Exclude $1.37 < \eta^{\text{cluster}} < 1.52$ | | ✓ | ✓ |
| Medium Layer identification | | ✓ | ✓ |
| HighPTrackOnly isolation | | ✓ | ✓ |
| $p_T > 20 \text{ GeV}$ | | | ✓ |
| Tight Layer identification | | | ✓ |
| FCTight isolation | | | ✓ |
| Unambiguous photon | | | ✓ |
| DFCommonAddAmbiguity ≤ 0 | | | ✓ |

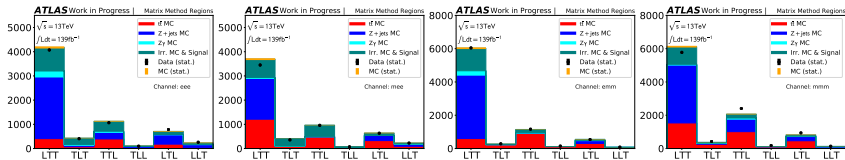
| Muon object selection | | | |
|---|--------------------|-------------|-------------|
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| $ \eta < 2.7$ | ✓ | ✓ | ✓ |
| Loose quality | ✓ | ✓ | ✓ |
| $ d_0^{\text{BL}}/\sigma(d_0^{\text{BL}}) < 3$ (for $ \eta < 2.5$ only) | ✓ | ✓ | ✓ |
| $ \Delta z_0^{\text{BL}} \sin \theta < 0.5 \text{ mm}$ (for $ \eta < 2.5$ only) | ✓ | ✓ | ✓ |
| PfLowLoose_FixedRad isolation | ✓ | ✓ | ✓ |
| μ -jet Overlap Removal | | ✓ | ✓ |
| $p_T > 15 \text{ GeV}$ | | ✓ | ✓ |
| $ \eta < 2.5$ | | ✓ | ✓ |
| Medium quality | | ✓ | ✓ |
| $p_T > 20 \text{ GeV}$ | | | ✓ |
| Tight quality | | | ✓ |
| PfLowTight_FixedRad isolation | | | ✓ |

Jet object selection

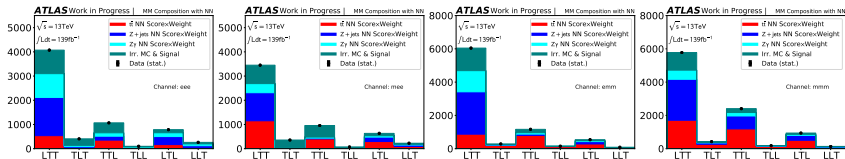
| | Selection |
|--|-----------|
| anti- $k_R \Delta R = 0.4$ | ✓ |
| $p_T > 25 \text{ GeV}$ | ✓ |
| JVT > 0.59 (for $p_T < 60 \text{ GeV}$ & $ \eta < 2.4$) | ✓ |
| ΔR (jet - baseline electron) ≥ 0.2 | ✓ |
| ΔR (jet with ≤ 3 tracks - baseline muon) ≥ 0.4 | ✓ |

Comparison of Expected - Neural Net compositions per channel

Expected MC Compositions



Neural Network score-based Composition





Comparison of Expected - Neural Net compositions per channel

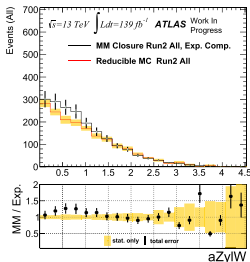
■ Results of MC closure with Exp. Comp. Weighted Average of FFs

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--|-------------------------------|-----------------------------|-------------------------------|-----------------------------|--------------------------------|
| $N_{LT} \cdot F_W$ | $478.3 \pm 11.0 \pm 108.9$ | $23.8 \pm 0.6 \pm 26.7$ | $683.5 \pm 12.8 \pm 153.2$ | $44.3 \pm 0.8 \pm 43.8$ | $1230.0 \pm 16.9 \pm 321.1$ |
| $N_{TL} \cdot F_Z$ | $87.7 \pm 13.1 \pm 36.1$ | $5.2 \pm 2.2 \pm 5.5$ | $7.8 \pm 0.6 \pm 1.7$ | $12.4 \pm 0.7 \pm 11.1$ | $113.1 \pm 13.3 \pm 43.5$ |
| $N_{TL} \cdot F_Z$ | $282.5 \pm 14.7 \pm 56.0$ | $87.6 \pm 5.8 \pm 15.9$ | $34.3 \pm 1.3 \pm 4.5$ | $90.8 \pm 2.2 \pm 14.1$ | $495.3 \pm 16.0 \pm 75.2$ |
| -2L Terms | $-59.3 \pm 2.8 \pm 20.1$ | $-2.7 \pm 0.2 \pm 1.7$ | $-2.2 \pm 0.1 \pm 0.8$ | $-0.6 \pm 0.0 \pm 0.4$ | $-64.8 \pm 2.8 \pm 22.5$ |
| Matrix Method result | $789.24 \pm 22.72 \pm 148.77$ | $113.99 \pm 6.25 \pm 35.13$ | $723.53 \pm 12.87 \pm 154.66$ | $146.92 \pm 2.44 \pm 58.62$ | $1773.68 \pm 26.96 \pm 372.33$ |
| $(\bar{t}\bar{t} + Z+jets + Z\gamma)$ MC \times SF | 565.80 ± 25.70 | 198.00 ± 6.60 | 695.50 ± 31.60 | 270.60 ± 9.20 | 1730.00 ± 42.30 |

■ Results of MC closure with NN-score Weighted Average of FFs

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--|-------------------------------|-------------------------------|-------------------------------|-----------------------------|--------------------------------|
| $N_{LT} \cdot F_W$ | $582.3 \pm 14.9 \pm 123.7$ | $20.9 \pm 0.5 \pm 13.8$ | $818.7 \pm 17.4 \pm 171.7$ | $39.7 \pm 0.7 \pm 27.2$ | $1461.6 \pm 22.9 \pm 312.0$ |
| $N_{TL} \cdot F_Z$ | $160.9 \pm 31.2 \pm 87.9$ | $-1.7 \pm 24.7 \pm 56.6$ | $7.4 \pm 0.5 \pm 1.8$ | $12.0 \pm 0.7 \pm 3.6$ | $178.7 \pm 39.8 \pm 130.9$ |
| $N_{TL} \cdot F_Z$ | $498.4 \pm 42.3 \pm 108.0$ | $215.6 \pm 35.6 \pm 91.8$ | $32.5 \pm 1.2 \pm 4.4$ | $85.8 \pm 2.1 \pm 12.1$ | $832.2 \pm 55.3 \pm 201.3$ |
| -2L Terms | $-284.6 \pm 32.4 \pm 112.8$ | $-34.1 \pm 22.7 \pm 28.4$ | $-2.0 \pm 0.1 \pm 0.6$ | $-0.6 \pm 0.0 \pm 0.4$ | $-321.3 \pm 39.6 \pm 137.7$ |
| Matrix Method result | $957.05 \pm 63.49 \pm 187.37$ | $200.67 \pm 48.89 \pm 138.76$ | $856.58 \pm 17.47 \pm 172.93$ | $137.00 \pm 2.35 \pm 39.78$ | $2151.30 \pm 82.05 \pm 454.55$ |
| $(\bar{t}\bar{t} + Z+jets + Z\gamma)$ MC \times SF | 565.80 ± 25.70 | 198.00 ± 6.60 | 695.50 ± 31.60 | 270.60 ± 9.20 | 1730.00 ± 42.30 |

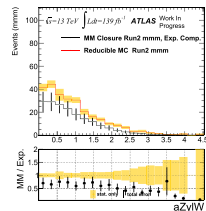
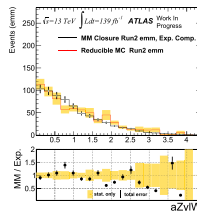
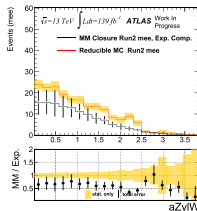
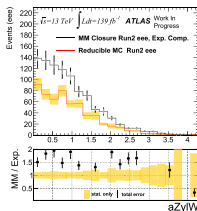
MC Closure Distributions - $|y_Z - y_{IW}|$



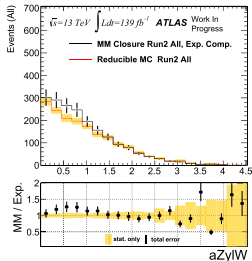
- Comparison of distribution of $|y_Z - y_{IW}|$ and Expected Reducible MC, scaled with MC Scale Factors.

- Per MC event, the weighted average of the 3 MC-derived FFs (weights being the Exp. MC composition) are used.

- Shown are MM stat. errors, MM total errors and MC stat. errors.



MC Closure Distributions - $|y_Z - y_{IW}|$



- Comparison of distribution of $|y_Z - y_{IW}|$ and Expected Reducible MC, scaled with MC Scale Factors.
- Per MC event, the weighted average of the 3 MC-derived FFs (weights being the Exp. MC composition) are used.
- Shown are MM stat. errors, MM total errors and MC stat. errors.

■ Results of MC closure with Exp. Comp. Weighted Average of FFs

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--|-------------------------------|-----------------------------|-----------------------------|-----------------------------|--------------------------------|
| $N_{IT} \cdot F_W$ | $461.4 \pm 6.5 \pm 49.7$ | $34.9 \pm 0.5 \pm 43.5$ | $627.0 \pm 7.0 \pm 55.6$ | $67.0 \pm 0.7 \pm 49.9$ | $1190.2 \pm 9.6 \pm 191.6$ |
| $N_{ITL} \cdot F_Z$ | $177.1 \pm 12.0 \pm 54.0$ | $9.2 \pm 0.4 \pm 0.4$ | $6.6 \pm 0.2 \pm 0.9$ | $11.0 \pm 0.3 \pm 18.3$ | $203.9 \pm 12.0 \pm 57.3$ |
| $N_{ITL} \cdot F_Z$ | $384.3 \pm 9.4 \pm 87.3$ | $86.2 \pm 1.6 \pm 2.4$ | $37.5 \pm 0.5 \pm 0.9$ | $100.0 \pm 1.2 \pm 1.5$ | $607.9 \pm 9.6 \pm 89.6$ |
| -2L Terms | $-65.4 \pm 1.9 \pm 9.4$ | $-2.8 \pm 0.1 \pm 0.2$ | $-2.4 \pm 0.1 \pm 0.7$ | $-0.5 \pm 0.0 \pm 0.4$ | $-71.2 \pm 1.9 \pm 9.8$ |
| Matrix Method result | $957.32 \pm 16.67 \pm 112.72$ | $127.53 \pm 1.70 \pm 43.57$ | $688.56 \pm 7.04 \pm 55.58$ | $177.45 \pm 1.45 \pm 53.19$ | $1930.86 \pm 18.23 \pm 225.69$ |
| $(\tilde{t}\tilde{t} + Z\text{jets} + Z\gamma)$ MC \times SF | 565.80 ± 25.70 | 198.00 ± 6.60 | 695.50 ± 31.60 | 270.60 ± 9.20 | 1730.00 ± 42.30 |

Systematics of MM with NN

Breakdown (NN)

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--|--------|----------|-----------|-------------|--------|
| Relative uncertainties [%] | | | | | |
| F_W muon | 0.00 | 1.12 | 0.00 | 3.54 | 0.33 |
| F_Z muon | 0.00 | 0.00 | 0.23 | 2.32 | 0.24 |
| F_W electron | 5.30 | 0.00 | 14.63 | 0.00 | 8.18 |
| F_Z electron | 1.03 | 9.96 | 0.00 | 0.00 | 1.19 |
| Correlated Irr. subtraction (CR) | 3.26 | 6.92 | 7.36 | 26.71 | 6.73 |
| Irr. subtraction (SR) | 17.05 | 67.45 | 5.59 | 2.46 | 16.26 |
| Correlated η correction (e) | 7.28 | 9.10 | 10.39 | 0.00 | 8.22 |
| Correlated η correction (μ) | 0.00 | 0.89 | 0.46 | 10.28 | 0.92 |
| W. Average Stat. Uncertainty | 0.00 | 0.00 | 0.00 | 0.00 | 0.00 |
| Total sys. | 19.58 | 69.15 | 20.19 | 29.04 | 21.13 |
| Stat. | 6.63 | 24.36 | 2.04 | 1.72 | 3.81 |
| Total | 20.67 | 73.31 | 20.29 | 29.09 | 21.47 |
| Absolute uncertainties | | | | | |
| Total | 197.84 | 147.12 | 173.81 | 39.85 | 461.90 |

Breakdown (Exp. Comp.)

| Source | eee | μee | $e\mu\mu$ | $\mu\mu\mu$ | All |
|--|--------|----------|-----------|-------------|--------|
| Relative uncertainties [%] | | | | | |
| F_W muon | 0.00 | 2.95 | 0.00 | 4.36 | 0.55 |
| F_Z muon | 0.00 | 0.00 | 0.32 | 2.31 | 0.31 |
| F_W electron | 3.18 | 0.00 | 5.29 | 0.00 | 3.56 |
| F_Z electron | 2.75 | 3.46 | 0.00 | 0.00 | 1.27 |
| Correlated Irr. subtraction | 14.28 | 26.32 | 17.40 | 35.61 | 17.43 |
| Correlated η correction (e) | 9.70 | 8.14 | 9.89 | 0.00 | 8.87 |
| Correlated η correction (μ) | 0.00 | 1.90 | 0.58 | 10.24 | 1.21 |
| W. Average Stat. Uncertainty | 6.27 | 12.89 | 5.29 | 13.97 | 6.48 |
| Total sys. | 18.85 | 30.82 | 21.38 | 39.90 | 20.99 |
| Stat. | 2.88 | 5.48 | 1.78 | 1.66 | 1.52 |
| Total | 19.07 | 31.30 | 21.45 | 39.94 | 21.05 |
| Absolute uncertainties | | | | | |
| Total | 150.49 | 35.68 | 155.19 | 58.68 | 373.30 |